

Automotive-grade N-channel 40 V, 1.46 mΩ typ., 120 A STripFET™ F6 Power MOSFETs in I²PAK and TO-220 packages

Datasheet - production data

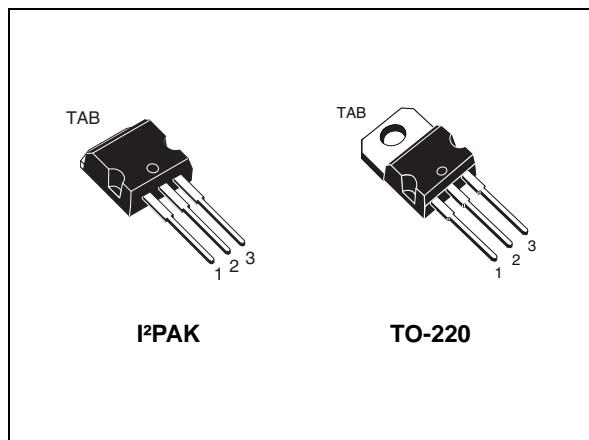
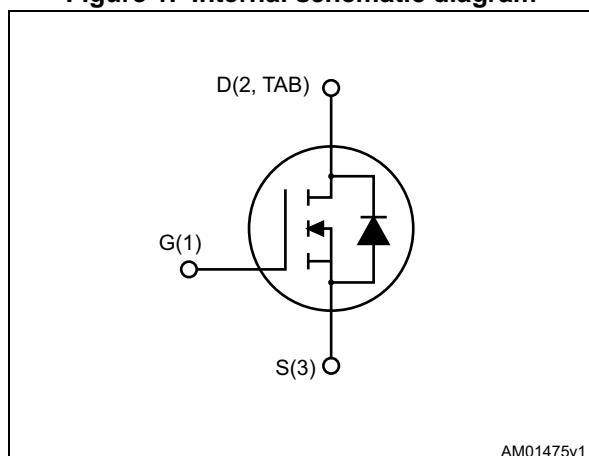


Figure 1. Internal schematic diagram



Features

Order codes	V _{DS}	R _{DS(on)} max.	I _D
STI360N4F6	40 V	1.8 mΩ	120 A
STP360N4F6			

- Designed for automotive applications and AEC-Q101 qualified
- Very low on-resistance
- Low gate charge
- High avalanche ruggedness
- Low gate drive power loss

Applications

- Switching applications

Description

These devices are N-channel Power MOSFETs developed using the STripFET™ F6 technology with a new trench gate structure. The resulting Power MOSFETs exhibit very low R_{DS(on)} in all packages.

Table 1. Device summary

Order codes	Marking	Packages	Packing
STI360N4F6	360N4F6	I ² PAK	Tube
STP360N4F6		TO-220	

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1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	40	V
V_{GS}	Gate-source voltage	± 20	V
$I_D^{(1)(2)}$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	120	A
	Drain current (continuous) at $T_C = 100^\circ\text{C}$	120	
$I_{DM}^{(1)}$	Drain current (pulsed)	480	A
P_{TOT}	Total dissipation at $T_C = 25^\circ\text{C}$	300	W
T_{stg}	Storage temperature	- 55 to 175	$^\circ\text{C}$
T_j	Operating junction temperature		

1. Current limited by package.
2. Pulse width is limited by safe operating area.

Table 3. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	0.5	$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	62.5	

2 Electrical characteristics

($T_{CASE} = 25^\circ\text{C}$ unless otherwise specified)

Table 4. Static

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	40			V
I_{DSS}	Zero gate voltage Drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 40 \text{ V}$			1	μA
		$V_{GS} = 0 \text{ V}, V_{DS} = 40 \text{ V}, T_C = 125^\circ\text{C}$			100	μA
I_{GSS}	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 0 \text{ V}$			± 100	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	3		4.5	V
$R_{DS(\text{on})}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 60 \text{ A}$		1.46	1.8	$\text{m}\Omega$

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	17800	-	pF
C_{oss}	Output capacitance		-	1750	-	
C_{rss}	Reverse transfer capacitance		-	1305	-	
Q_g	Total gate charge	$V_{DD} = 20 \text{ V}, I_D = 120 \text{ A}, V_{GS} = 10 \text{ V}$ (see Figure 14: Gate charge test circuit)	-	304	-	nC
Q_{gs}	Gate-source charge		-	96	-	
Q_{gd}	Gate-drain charge		-	87	-	

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(\text{on})}$	Turn-on delay time	$V_{DD} = 20 \text{ V}, I_D = 60 \text{ A}$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 13: Switching times test circuit for resistive load and Figure 18: Switching time waveform)	-	64	-	ns
t_r	Rise time		-	182	-	
$t_{d(\text{off})}$	Turn-off-delay time		-	240	-	
t_f	Fall time		-	130	-	

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}^{(1)}$	Source-drain current		-		120	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		480	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 120 \text{ A}, V_{GS} = 0 \text{ V}$	-		1.3	V
t_{rr}	Reverse recovery time	$I_{SD} = 120 \text{ A}, V_{DD} = 32 \text{ V}$ $di/dt = 100 \text{ A}/\mu\text{s},$ $T_j = 25^\circ\text{C}$ (see <i>Figure 15: Test circuit for inductive load switching and diode recovery times</i>)	-	44		ns
Q_{rr}	Reverse recovery charge		-	47		nC
I_{RRM}	Reverse recovery current		-	2.1		A

1. Current limited by package
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%

2.1 Electrical characteristics (curves)

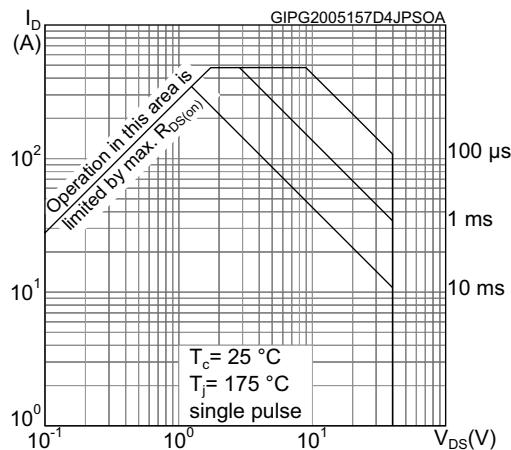
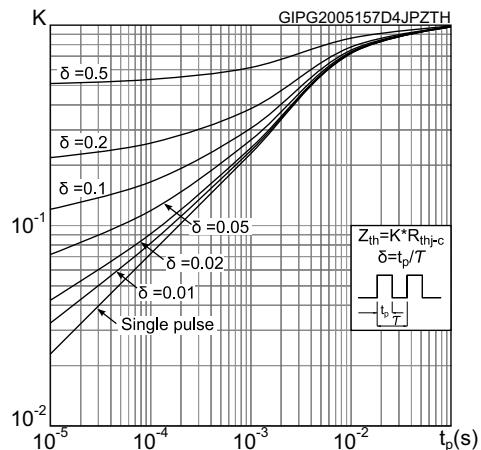
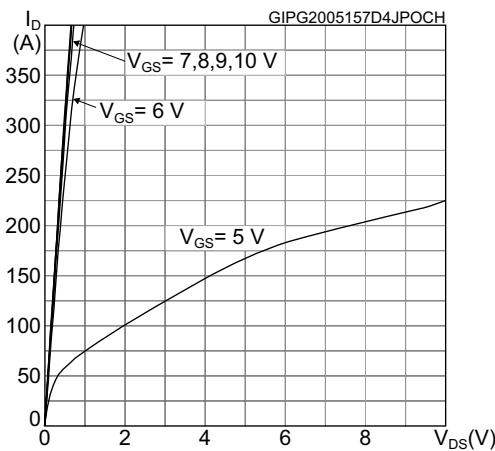
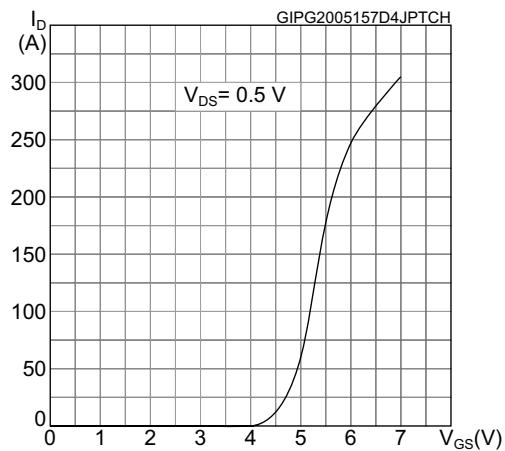
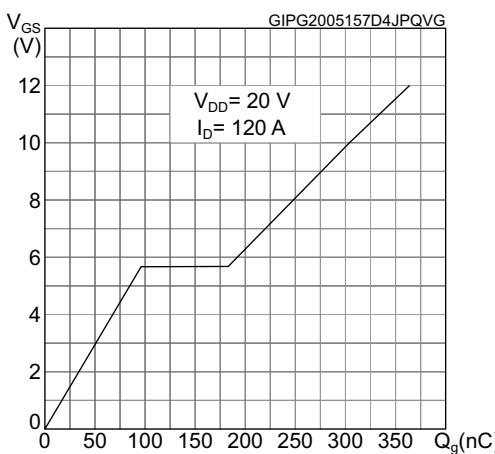
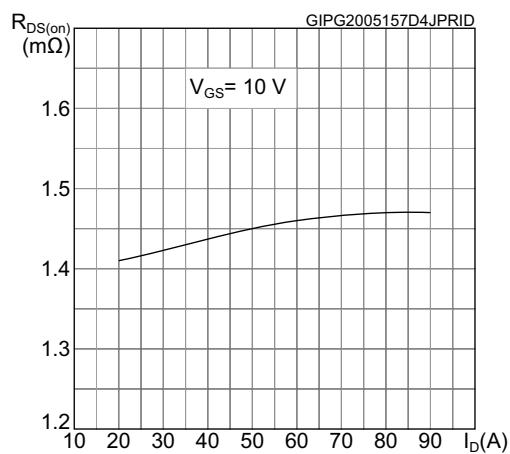
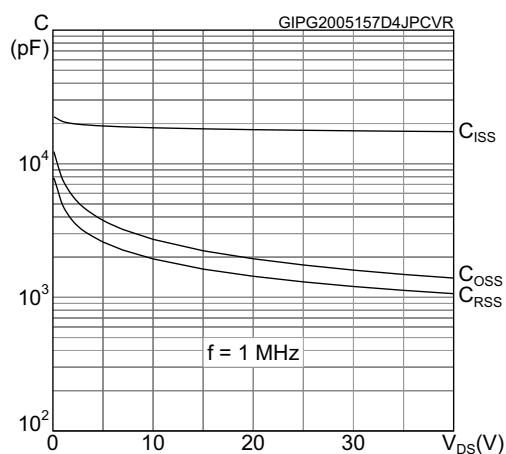
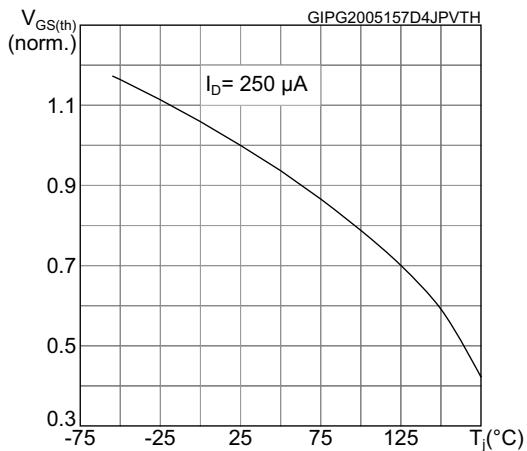
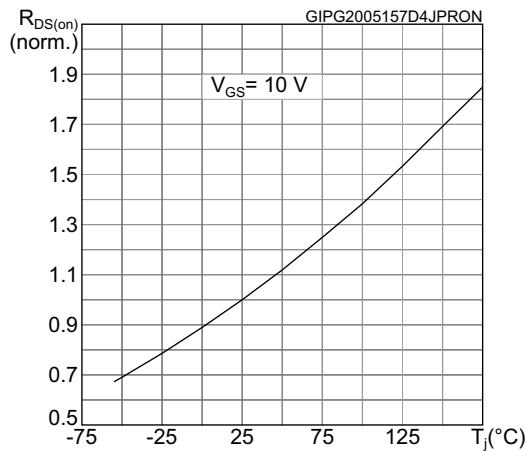
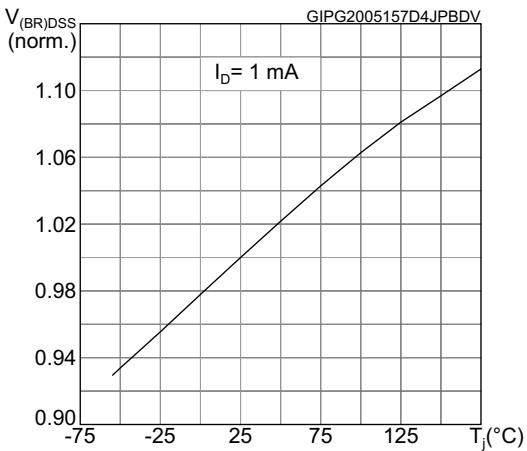
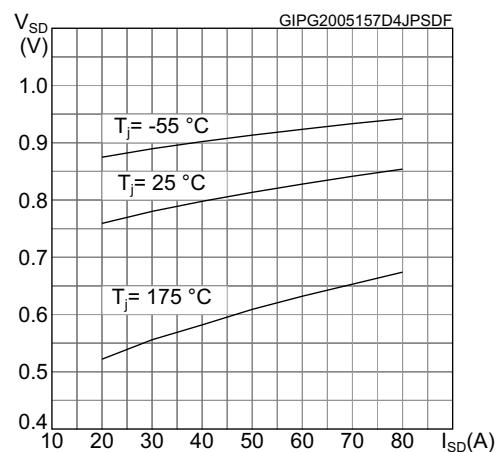
Figure 2. Safe operating area**Figure 3. Thermal impedance****Figure 4. Output characteristics****Figure 5. Transfer characteristics****Figure 6. Gate charge vs gate-source voltage****Figure 7. Static drain-source on-resistance**

Figure 8. Capacitance variations**Figure 9. Normalized gate threshold voltage vs temperature****Figure 10. Normalized on-resistance vs temperature****Figure 11. Normalized $V_{(BR)DSS}$ vs temperature****Figure 12. Source-drain diode forward characteristics**

3 Test circuits

Figure 13. Switching times test circuit for resistive load

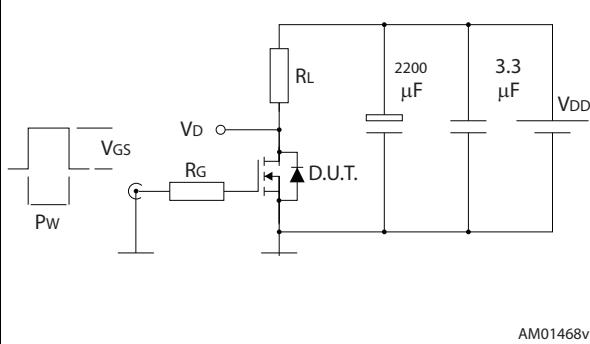


Figure 14. Gate charge test circuit

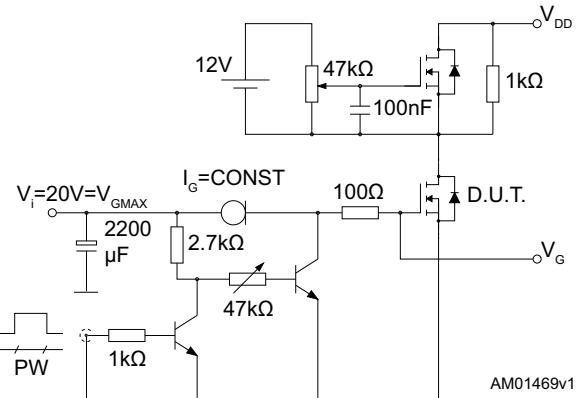


Figure 15. Test circuit for inductive load switching and diode recovery times

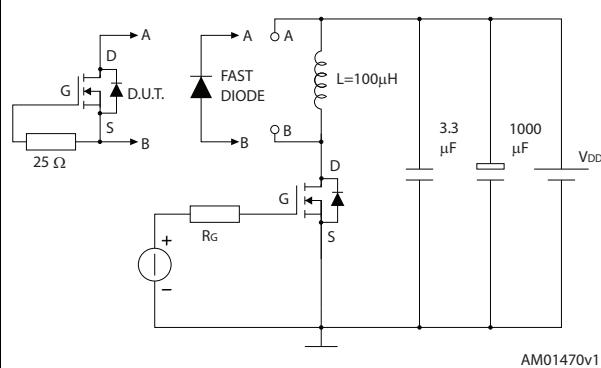


Figure 16. Unclamped inductive load test circuit

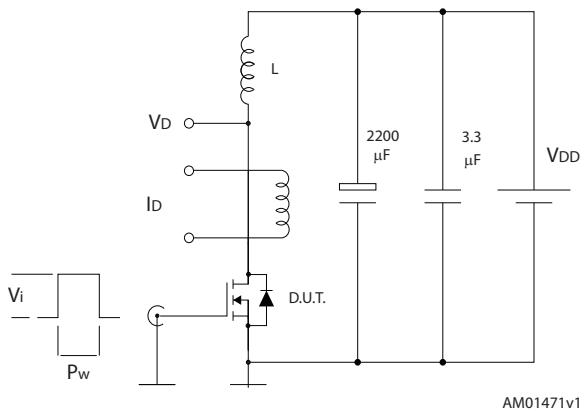


Figure 17. Unclamped inductive waveform

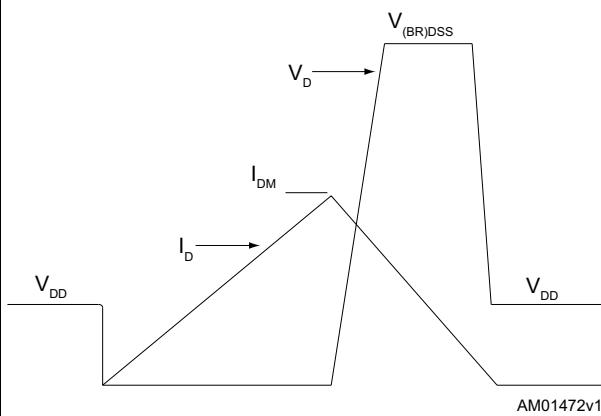
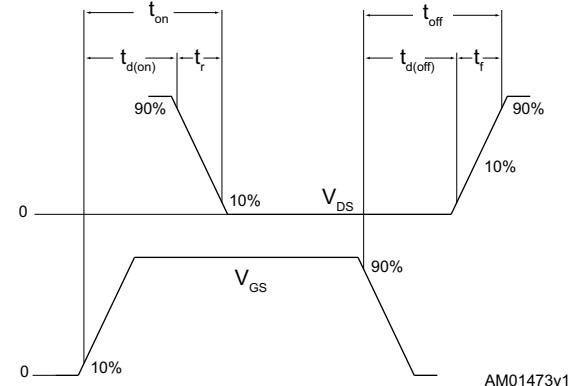


Figure 18. Switching time waveform



4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com.
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4.1 I²PAK package information

Figure 19. I²PAK (TO-262) package outline

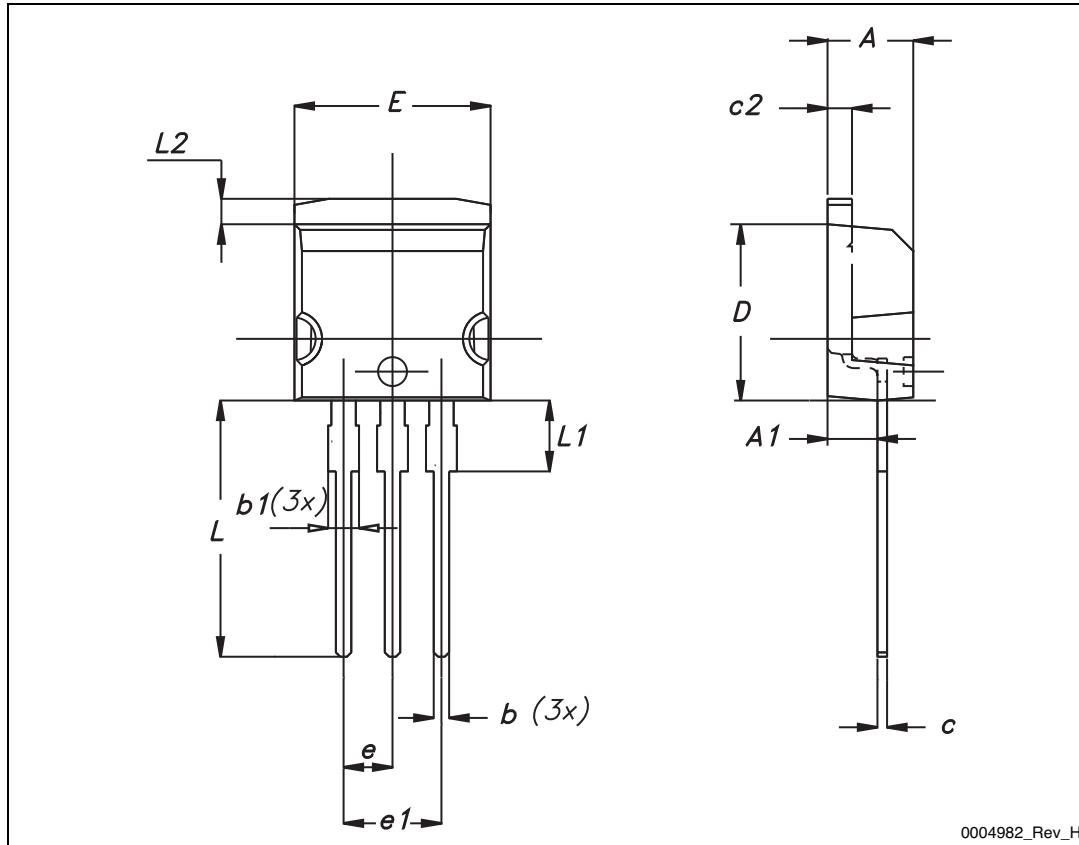


Table 8. I²PAK (TO-262) package mechanical data

DIM.	mm.		
	min.	typ	max.
A	4.40		4.60
A1	2.40		2.72
b	0.61		0.88
b1	1.14		1.70
c	0.49		0.70
c2	1.23		1.32
D	8.95		9.35
e	2.40		2.70
e1	4.95		5.15
E	10		10.40
L	13		14
L1	3.50		3.93
L2	1.27		1.40

4.2 TO-220 package information

Figure 20. TO-220 type A package outline

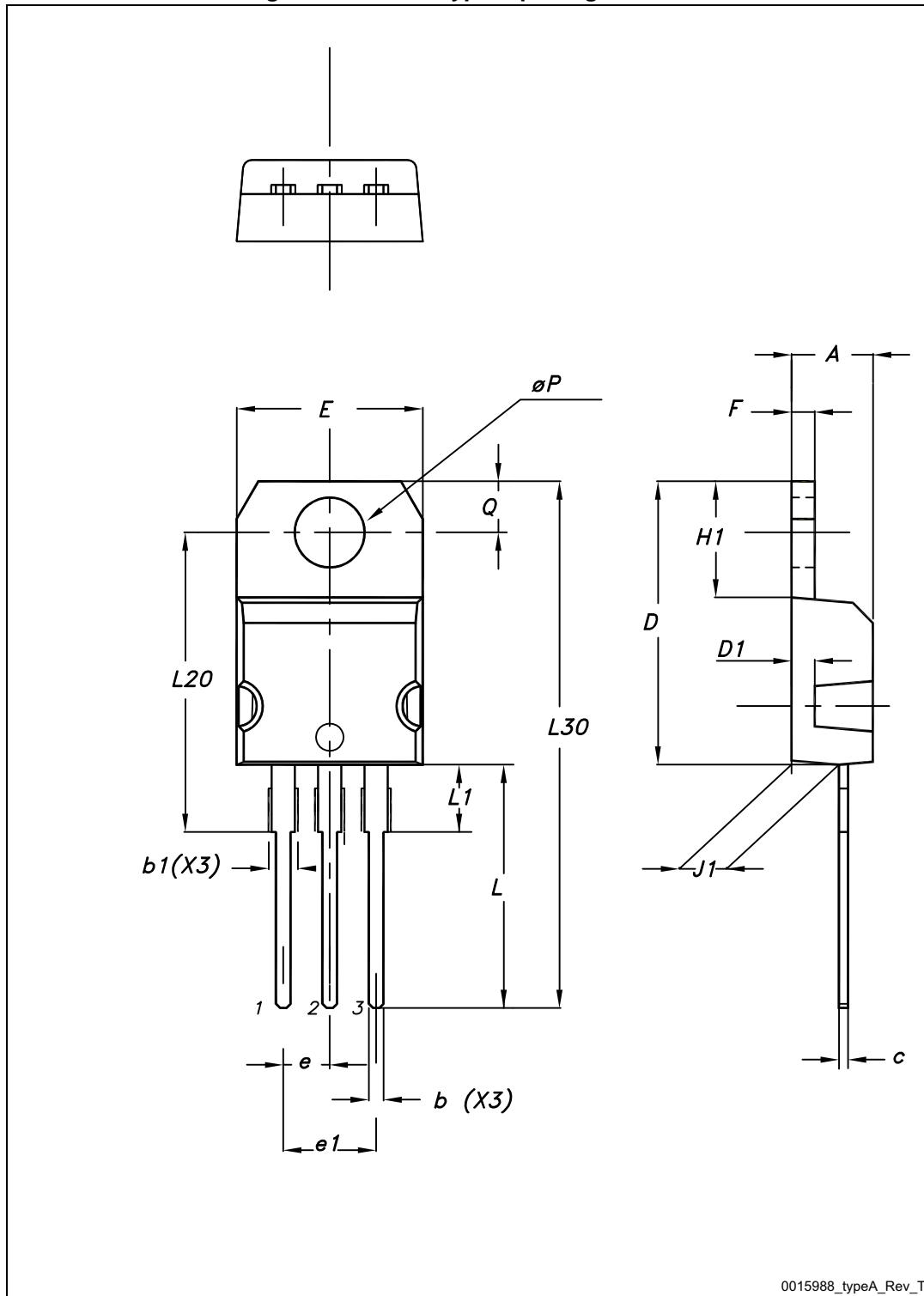


Table 9. TO-220 type A package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
b	0.61		0.88
b1	1.14		1.70
c	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10		10.40
e	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13		14
L1	3.50		3.93
L20		16.40	
L30		28.90	
ØP	3.75		3.85
Q	2.65		2.95

5 Revision history

Table 10. Document revision history

Date	Revision	Changes
08-Aug-2012	1	First release.
03-Dec-2015	2	Text and formatting changes throughout document Updated Section 1: Electrical ratings Updated Section 2: Electrical characteristics Added: Section 2.1: Electrical characteristics (curves) Added: Section 3: Test circuits

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